

<b>Notice of References Cited</b>	Application/Control No. 09/744,084	Applicant(s)/Patent Under Reexamination LAPPE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,533,012 A	07-1996	Fukasawa et al.	370/342
	B	US-5,377,194 A	12-1994	Calderbank, Arthur R.	370/524
	C	US-6,256,497 B1	07-2001	Chambers, Paul	455/433
	D	US-6,134,220 A	10-2000	Le Strat et al.	370/252
	E	US-6,339,601 B1	01-2002	Seong et al.	370/503
	F	US-5,689,245	11-1997	Noreen et al.	340/825.49
	G	US-6,021,518 A	02-2000	Pelz, Rodolfo Mann	714/799
	H	US-5,687,165	11-1997	Daffara et al.	370/208
	I	US-5,701,294	12-1997	Ward et al.	370/252
	J	US-6,112,084	08-2000	Sicher et al.	370/337
	K	US-6,016,428	01-2000	Diachina et al.	455/435.1
	L	US-5,729,531	03-1998	Raith et al.	370/252
	M	US-5,757,813	05-1998	Raith, Alex Krister	714/708

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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